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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant : Young-Geun PARK et al.  
Appl. No. : National Phase of PCT/KR04/00741  
Filed : Entry papers filed herewith: January 6, 2005  
Title : PROBE FOR A SCANNING PROBE MICROSCOPE  
AND METHOD FOR FABRICATING SAME

Docket No.: Docket No.: PARK3031/REF  
Customer No: Customer No.: 23364

**PRELIMINARY AMENDMENT**

MS PCT Office  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

The present application is the U.S. national phase of international application number PCT/KR04/00741.

Please amend the above-identified application as follows:

Amendments to the claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks begin on page 5 of this paper.